



Future Normal in Semiconductor

2025-02-14(금), 09:00-10:45

좌장: 추후업데이트 예정

F. Silicon and Group-IV Devices and Integration Technology 분과

[FH1-F] 3D GAA/CFET Technology

<p>FH1-F-1 09:00-09:15</p>	<p>Low-Temperature Fabrication of Silicon Nanowire GAAFETs with Excimer Laser Recrystallization for M3D Integration</p> <p>Jeong Yeon Im¹, Hanbin Lee¹, Gyeongsu Min¹, Hyo-In Yang¹, So Jeong Park¹, Jun-Ho Jang¹, Ji Won Park¹, Seonghyeon Jeong¹, Dae Hwan Kim¹, Jong-Ho Bae¹, Dong Myong Kim³, Min-Ho Kang², and Sung-Jin Choi¹</p> <p>¹School of Electrical Engineering, Kookmin University, ²Department of Nano-process, NNFC, ³Department of Advanced Technology, DGIST</p>
<p>FH1-F-2 09:15-09:30</p>	<p>Strained Ge/Si Heterogeneous 3D Sequential CFET Featuring First Strain Engineered Ge Top Channel</p> <p>Hyeongrak Lim¹, Seong Kwang Kim¹, Seung Woo Lee¹, Youngkeun Park¹, Jaejoong Jeong¹, Hojin Jeong¹, Jinha Lim¹, Dae-Myeong Geum², Jaehoon Han³, Younghyun Kim⁴, Jaeyong Jeong¹, Byung Jin Cho¹, and Sanghyeon Kim¹</p> <p>¹KAIST, ²Inha University, ³KIST, ⁴Hanyang University</p>
<p>FH1-F-3 09:30-09:45</p>	<p>Photoresponsive GIDL Characterization for Simultaneous Extraction of Donor- and Acceptor-like Interface Trap States in Vertically Stacked Si-NW GAA FETs</p> <p>Seohyeon Park¹, Donghyeon Lee¹, Jaewook Yoo¹, Minah Park¹, Hongseung Lee¹, Hyeonjun Song¹, Soyeon Kim¹, Seongbin Lim¹, Sojin Jung¹, Hagyoul Bae¹, Yang-Kyu Choi², and TaeWan Kim³</p> <p>¹Jeonbuk National University, ²KAIST, ³University of Seoul</p>
<p>FH1-F-4 09:45-10:00</p>	<p>Transient Analysis of CFET Inverter with Backside Interconnections : Buried Power Rails, Bottom Contacts</p> <p>Seung-Woo Jung and Sung-Min Hong</p> <p>School of Electrical Engineering and Computer Science, GIST</p>
<p>FH1-F-5 10:00-10:15</p>	<p>Implementation of a Stress Calculation Module in an In-House Process Emulator for Monolithic CFET</p> <p>Min-Seo Jang¹, In Ki Kim¹, Seung-Woo Jung¹, Jeong Hyeon Yun², Myoung Jin Lee², and Sung-Min Hong¹</p> <p>¹School of Electrical Engineering and Computer Science, GIST, ²Department of Electronic Engineering, Chonnam National University</p>



제 32회 한국반도체학술대회

The 32nd Korean Conference on Semiconductors

2025년 2월 12일(수)-14일(금) | 강원도 하이원리조트

Future Normal in Semiconductor

<p>FH1-F-6 10:15-10:30</p>	<p>A Novel 3D-SRAM Architecture based on VGAA Transistors for Advanced AI and Edge Computing Applications Changwoo Han and Changhwan Shin School of Electrical Engineering, College of Engineering, Korea University</p>
<p>FH1-F-7 10:30-10:45</p>	<p>Multi-Vth through Different Inner Gates Work Functions Seungjoon Jeong, Haevin Choi, and Changhwan Shin School of Electrical Engineering, Korea University</p>